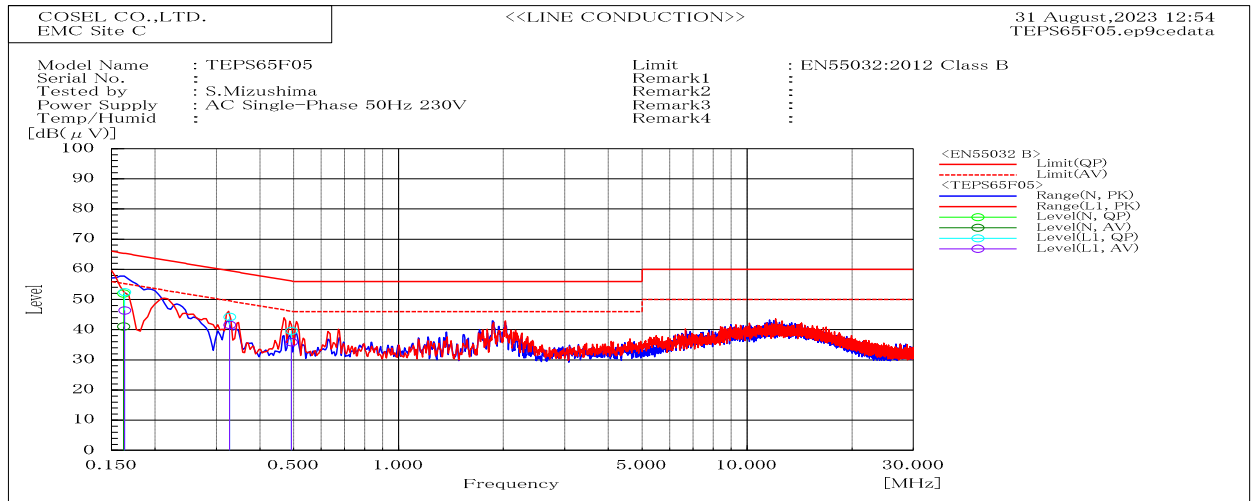
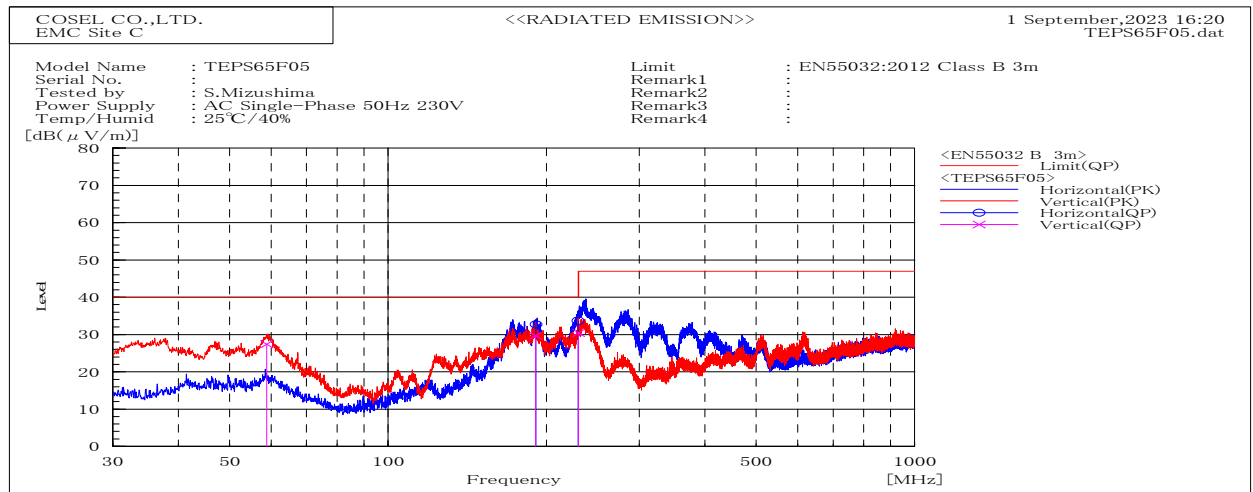


DATA SHEET		Date	12-Oct-23
Model	TEPS65F05	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mizushima



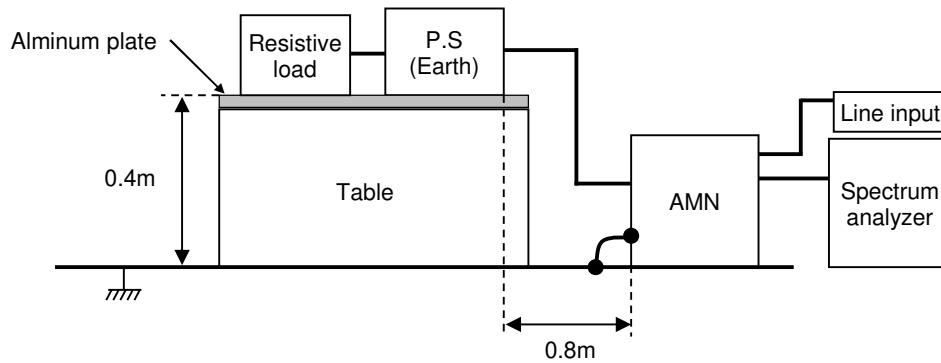
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.163	N	52	41	65.3	55.3	13.3	14.3	Pass	
0.164	L1	52.5	46.4	65.3	55.3	12.8	8.9	Pass	
0.328	L1	44.2	41.6	59.5	49.5	15.3	7.9	Pass	
0.493	L1	39.6	35.8	56.1	46.1	16.5	10.3	Pass	



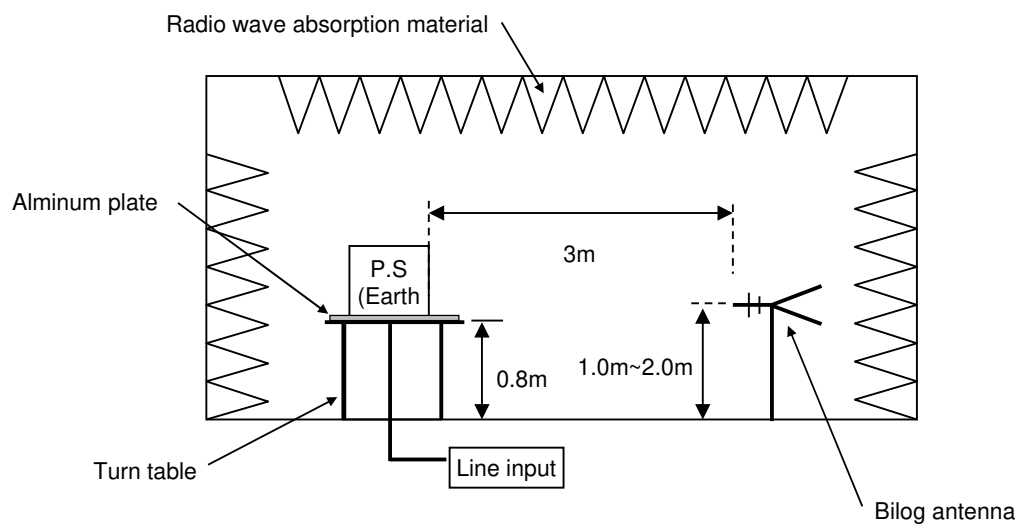
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB		cm	deg	
			QP	QP	QP				
190.924	H	Stable	32.7	40	7.3	Pass	199.7	272.9	
229.523	H	Stable	33.7	40	6.3	Pass	142.5	251.9	
58.787	V	Stable	27.4	40	12.6	Pass	100.2	0	
190.513	V	Stable	29.7	40	10.3	Pass	100.2	247.6	
229.891	V	Stable	30.5	40	9.5	Pass	100.2	244.2	

DATA SHEET		Date	12-Oct-23
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mizushima

### 1. Line conduction



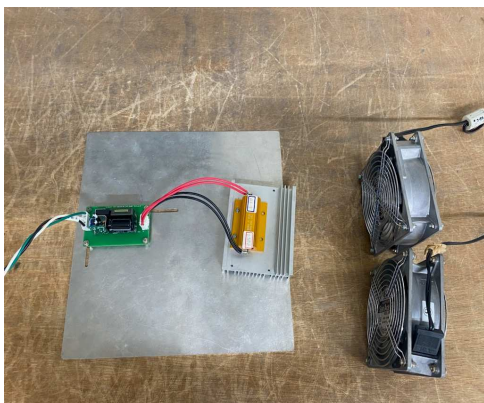
### 2. Radiated emission



## Conditions

Test : EMI  
Model Nam: TEPS65F05

### 1.LINE CONDUCTION



### 2.RADIATED EMISSION

